# 2009 14th IEEE European Test Symposium

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**Table of Contents**

# 2009 European Test Symposium

# ETS 2009

## Internal Testing of Mixed-Signal Cores

## Debug and Validation

## Power Issues during Test

## Selt-Test and Test Throughput

## On-Line Testing

## Advanced Testing of Memories, Power Transistors and Microfluidic Systems

## Recent Advances in ATPG

## Advanced External Testing of Mixed-Signals Cores

## Diagnosis and Dependability Analysis

# Impact of Nanometer Technologies in the Testing Methodology

# DfT and Embedded Test

# ETS 2008 Best Paper

# Author Index